

Preface

This volume represents presentations given at the 80th annual meeting of the Psychometric Society, organized by the Beijing Normal University, during July 12–16, 2015. The meeting attracted 511 participants from 21 countries, with 254 papers being presented, along with 119 poster presentations, three pre-conference workshops, four keynote presentations, eight invited presentations, and six invited and five contributed symposia. This meeting was the first ever held in China, the birthplace of standardized testing, as was highlighted in the keynote address “the history in standardized testing” by Dr. Houcan Zhang. We thank the local organizers Tao Xin and Hongyun Liu and their staff and students for hosting this very successful conference.

Since the 77th meeting in Lincoln, Nebraska, Springer publishes the proceedings volume from the annual meeting of the Psychometric Society so as to allow presenters to quickly make their ideas available to the wider research community, while still undergoing a thorough review process. The first three volumes of the meetings in Lincoln, Arnhem, and Madison were received successfully, and we expect a successful reception of these proceedings too.

We asked authors to use their presentation at the meeting as the basis of their chapters, possibly extended with new ideas or additional information. The result is a selection of 29 state-of-the-art chapters addressing a diverse set of topics, including item response theory, factor analysis, structural equation modelling, time series analysis, mediation analysis, cognitive diagnostic models, and multi-level models.

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Hong Kong, China
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